

**IN THE DRAWINGS**

Per the request of the Examiner, Applicants include herewith a copy of amended FIG. 1 to include the PRIOR ART notation in red ink, attached hereto as Exhibit A.

**IN THE CLAIMS**

Please cancel claim 21.

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Please amend claim 22 as follows:

22. (Amended) The specimen inspection system of claim 12, wherein said pinhole mask is mounted adjacent to the time delay and integration charge coupled device.

C l [Please amend claim 23 as follows:]

23. (Amended) The specimen inspection system of claim 12, further comprising a focusing lens, wherein said focusing lens receives light energy from said pinhole mask and focuses light energy onto said time delay and integration charge coupled device.

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